## Notice of References Cited Application/Control No. 10/717,421 Examiner James M. Mitchell Applicant(s)/Patent Under Reexamination BOON ET AL. Art Unit 2813 Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2003/0080398	05-2003	Badehi, Avner	257/678
	В	US-6,876,061	04-2005	Zandman et al.	257/620
	С	US-2003/0134453	07-2003	Prabhu et al.	438/113
	D	US-2004/0251525	12-2004	Zilber et al.	257/678
	Е	US-6,552,426	04-2003	Ishio et al.	257/692
	F	US-6,379,999	04-2002	Tanabe, Shinji	438/113
	G	US-6,710,454	03-2004	Boon, Suan Jeung	257/777
	Ι	US-2004/0140573	07-2004	Pu et al.	257/782
	-	US-6,841,418	01-2005	Jeung et al.	438/108
	7	US-			
	К	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	s					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)						
	U							
	٧							
	w							
	х							

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.